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Editorial
V.D. Agrawal **263**

Test Technology Newsletter **265**

AUTOMOTIVE TESTING

Modular Test Kit – A Modular Approach for Efficient and Function-Oriented Testing
B. Jooß · D. Schramm **267**

SINGLE EVENT UPSET (SEU) AND RADIATION HARDENING

Investigation of Single Event Effects in a Resistive RAM Memory Array by Coupling TCAD and SPICE Simulations
K. Coulié · H. Aziza · W. Rahajandraibe **275**

Low Overhead and High Stability Radiation-Hardened Latch for Double/Triple Node Upsets
Z. Huang · H. Wang · D. Ma · H. Liang · Y. Ouyang · A. Yan **289**

ANALOG AND RF CIRCUIT TESTING

BISCC: A Novel Approach to Built In State Consistency Checking For Quick Volume Validation of Mixed-Signal/RF Systems
S. Deyati · B. Muldrey · A. Chatterjee **303**

BRIDGING FAULTS

A Flexible Concurrent Testing Scheme for Non-Feedback and Feedback Bridging Faults in Integrated Circuits
P.K. Biswal **323**

SOFTWARE TESTING

A Novel Metaheuristic Based Method for Software Mutation Test Using the Discretized and Modified Forrest Optimization Algorithm
B. Arasteh · F.S. Gharehchopogh · P. Gunes · F. Kiani · M. Torkamanian-Afshar **347**

HARDWARE SECURITY

Multi-Objective Optimization Based Test Pattern Generation for Hardware Trojan Detection
V.S. Rathor · D. Singh · S. Singh · M. Sajwan **371**

SYSTEM-ON-CHIP TESTING

Incomplete Testing of SOC
K.M. Singh · J. Deka · S. Biswas **387**

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